



2 – 4 June



Bristol (United Kingdom)



3 – 5 June



Bristol Marriott Royal Hotel

WOCSDICE 2020

44th Workshop on Compound Semiconductor Devices and Integrated Circuits held in Europe

EXMATEC 2020

15th Expert evaluation and Control of Compounds of Semiconductor Materials and Technologies

Learn and share ideas on state-of-the-art research and latest advancements on:

- Compound semiconductor-based devices including wide bandgap semiconductors
- One- (1D) and two-dimensional (2D) layered devices and their materials
- Device modelling, processing, reliability, packaging and characterization
- High-frequency, power and optoelectronic devices
- Applications of devices and structures
- Novel device and circuit concepts
- Low dimensional semiconductor systems
- Bulk & epitaxial growth and defects
- III-Vs, III-Ns, II-VIs, SiC, SiGe
- Nanostructures (physics & materials)
- RF and power electronic materials
- Advanced characterization techniques
- Interfaces & heterostructures
- Photovoltaic and optoelectronic materials
- Reliability issues (physics of failure and degradation mechanisms)

Confirmed invited speakers:

WOCSDICE:

Daniel Granados, IMDEA, Spain
Rashaunda Henderson, UT Dallas, USA
Bob Kaplar, Sandia, USA
Joana Caterina Mendes, University of Aveiro, Portugal
Clemens Ostermaier, Infineon, Austria

WOCSDICE & EXMATEC:

David Eon, NEEL, France
Henri Happy, IEMN, France
Masataka Higashiwaki, NICT, Japan
Raffaella Lo Nigro, CNR, Italy

EXMATEC:

Vanya Darakchieva, University of Linköping, Sweden
Eva Monroy, CEA, France
N. Ben Sedrine, University of Aveiro, Portugal
Zlatko Sitar, NCSU, USA

Key dates to remember:

1 March 2020: Short abstract submission deadline
5 April 2020: Notification of acceptance
20 April 2020: Early registration deadline with reduced fees
24 April 2020: Extended abstract submission deadline

For more information please visit our continuously updated website:

www.wocsdice-exmatec-2020.com

For any enquiry please contact:

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